

**Search Notes**

Application/Control No.

10/062,700

Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

LAU ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
709	223	2/17/2006	DB
370	395	2/17/2006	DB
370	466	2/17/2006	DB
370	400	2/17/2006	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	2/17/2006	DB